

# HB56D51232 Series — 512 D ■ 4496203 0019110 435 ■ HIT2

524,288-Word x 32-Bit High Density Dynamic RAM Module

HITACHI/ LOGIC/ARRAYS/MEM

## ■ DESCRIPTION

The HB56D51232SB is a 512k x 32 dynamic RAM module, mounted 16 pieces of 1 Mbit DRAM (HM514256JP) sealed in SOJ package. An outline of the HB56D51232SB is 72-pin single in-line package. Therefore, the HB56D51232SB makes high density mounting possible without surface mount technology. The HB56D51232SB provides common data inputs and outputs.

Decoupling capacitors are mounted beneath each SOJ but only on the one side of its module board.

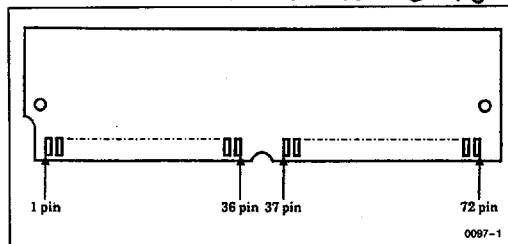
## ■ FEATURES

- 72-pin Single In-line Package  
Lead Pitch ..... 1.27mm
- Single 5V (±5%) Supply
- High Speed  
Access Time ..... 60 ns/70 ns/80 ns/100 ns/  
120 ns (max)
- Low Power Dissipation  
Active Mode ..... 3.95W/3.57W/2.982W/2.52W/  
2.184W (max)  
Standby Mode ..... 168 mW (max)
- Fast Page Capability
- 512 Refresh Cycles/8 ms
- 2 Variations of Refresh  
RAS Only Refresh  
CAS Before RAS Refresh
- TTL Compatible

## ■ ORDERING INFORMATION

Part No.	Access Time	Package
HB56D51232SB-6A	60 ns	72-pin SIP Socket Type
HB56D51232SB-7A	70 ns	
HB56D51232SB-8A	80 ns	
HB56D51232SB-10A	100 ns	
HB56D51232SB-12A	120 ns	

## ■ PIN OUT



Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name
1	V <sub>SS</sub>	19	NC	37	NC	55	DQ <sub>11</sub>
2	DQ <sub>0</sub>	20	DQ <sub>4</sub>	38	NC	56	DQ <sub>27</sub>
3	DQ <sub>16</sub>	21	DQ <sub>20</sub>	39	V <sub>SS</sub>	57	DQ <sub>12</sub>
4	DQ <sub>1</sub>	22	DQ <sub>5</sub>	40	CAS <sub>0</sub>	58	DQ <sub>28</sub>
5	DQ <sub>17</sub>	23	DQ <sub>21</sub>	41	CAS <sub>2</sub>	59	V <sub>CC</sub>
6	DQ <sub>2</sub>	24	DQ <sub>6</sub>	42	CAS <sub>3</sub>	60	DQ <sub>29</sub>
7	DQ <sub>18</sub>	25	DQ <sub>22</sub>	43	CAS <sub>1</sub>	61	DQ <sub>13</sub>
8	DQ <sub>3</sub>	26	DQ <sub>7</sub>	44	RAS <sub>0</sub>	62	DQ <sub>30</sub>
9	DQ <sub>19</sub>	27	DQ <sub>23</sub>	45	RAS <sub>1</sub>	63	DQ <sub>14</sub>
10	V <sub>CC</sub>	28	A <sub>7</sub>	46	NC	64	DQ <sub>31</sub>
11	NC	29	NC	47	WE	65	DQ <sub>15</sub>
12	A <sub>0</sub>	30	V <sub>CC</sub>	48	NC	66	NC
13	A <sub>1</sub>	31	A <sub>8</sub>	49	DQ <sub>8</sub>	67	NC
14	A <sub>2</sub>	32	NC	50	DQ <sub>24</sub>	68	V <sub>SS</sub>
15	A <sub>3</sub>	33	RAS <sub>3</sub>	51	DQ <sub>9</sub>	69	PD <sub>1</sub>
16	A <sub>4</sub>	34	RAS <sub>2</sub>	52	DQ <sub>25</sub>	70	PD <sub>2</sub>
17	A <sub>5</sub>	35	NC	53	DQ <sub>10</sub>	71	NC
18	A <sub>6</sub>	36	NC	54	DQ <sub>26</sub>	72	V <sub>SS</sub>

## ■ PIN DESCRIPTION

Pin Name	Function
A <sub>0</sub> -A <sub>8</sub>	Address Input
A <sub>0</sub> -A <sub>8</sub>	Refresh Address Input
DQ <sub>0</sub> -DQ <sub>31</sub>	Data-in/Data-out
CAS <sub>0</sub> -CAS <sub>3</sub>	Column Address Strobe
RAS <sub>0</sub> -RAS <sub>3</sub>	Row Address Strobe
WE	Read/Write Enable
V <sub>CC</sub>	Power Supply (+ 5V)
V <sub>SS</sub>	Ground
NC	No Connection

## ■ PRESENCE DETECT PINOUT

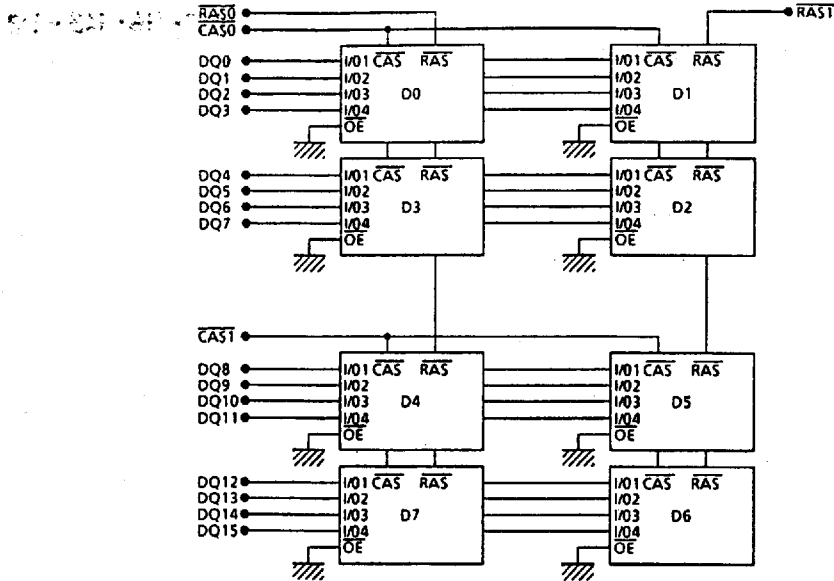
Pin No.	Pin Name	HB56D51232SB				
		60 ns	70 ns	80 ns	100 ns	120 ns
69	PD <sub>1</sub>	NC	V <sub>SS</sub>	NC	V <sub>SS</sub>	NC
70	PD <sub>2</sub>	NC	NC	V <sub>SS</sub>	V <sub>SS</sub>	NC



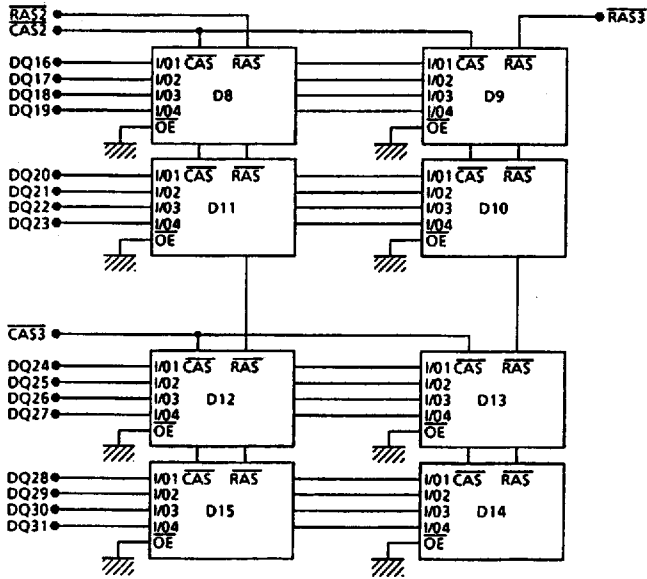
BLOCK DIAGRAM

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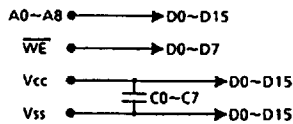
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0067-3



\* D0~D15 : HM514256

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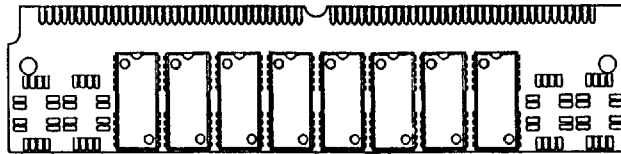
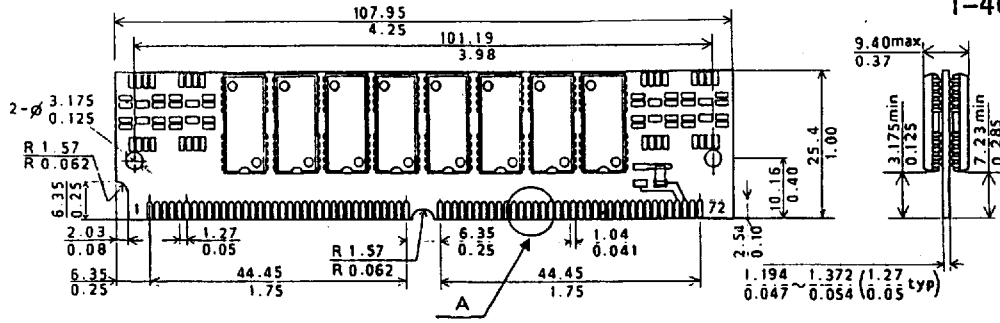


■ PACKAGE OUTLINE

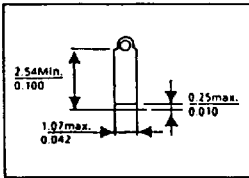
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Unit: mm/inch

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Detail A



0067-5

Note: Contact finish 2.2  $\mu$ m (86.6  $\mu$ inch) Solder over 2.0  $\mu$ m (78.7  $\mu$ inch) Ni.

■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit	
Voltage on Any Pin Relative to $V_{SS}$	(Input)	V	- 1.0 to +7.0	V
	(Output)	$V_{OHt}$	- 1.0 to +7.0	V
Supply Voltage Relative to $V_{SS}$	$V_{CC}$	- 1.0 to +7.0	V	
Short Circuit Output Current	$I_{out}$	50	mA	
Power Dissipation	$P_T$	16	W	
Operating Temperature	$T_{opr}$	0 to +70	$^{\circ}$ C	
Storage Temperature	$T_{stg}$	- 55 to +125	$^{\circ}$ C	

■ ELECTRICAL CHARACTERISTICS

• Recommended DC Operating Conditions ( $T_A = 0$  to +70 $^{\circ}$ C)

Parameter	Symbol	Min	Typ	Max	Unit	Note
Supply Voltage	$V_{SS}$	0	0	0	V	
	$V_{CC}$	4.75	5.0	5.25	V	1
Input High Voltage	$V_{IH}$	2.4	—	5.5	V	1
Input Low Voltage	$V_{IL}$	- 1.0	—	0.8	V	1

Note: 1. All voltage referenced to  $V_{SS}$ .



• DC Electrical Characteristics (T<sub>A</sub> = 0 to +70°C, V<sub>CC</sub> = 5V ± 5%, V<sub>SS</sub> = 0V)

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Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Test Condition	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max			
Operating Current	I <sub>CC1</sub>	—	760	—	680	—	568	—	480	—	416	mA	t <sub>RC</sub> = min	1, 2
Standby Current	I <sub>CC2</sub>	—	32	—	32	—	32	—	32	—	32	mA	TTL Interface RAS, CAS = V <sub>IH</sub> D <sub>out</sub> = High-Z	
		—	16	—	16	—	16	—	16	—	16	mA	CMOS Interface RAS, CAS ≥ V <sub>CC</sub> - 0.2V D <sub>out</sub> = High-Z	
RAS Only Refresh Current	I <sub>CC3</sub>	—	760	—	680	—	568	—	480	—	416	mA	t <sub>RC</sub> = min	2
Standby Current	I <sub>CC5</sub>	—	80	—	80	—	80	—	80	—	80	mA	RAS = V <sub>IH</sub> CAS = V <sub>IL</sub> D <sub>out</sub> = Enable	
CAS Before RAS Refresh Current	I <sub>CC6</sub>	—	760	—	680	—	568	—	480	—	416	mA	t <sub>RC</sub> = min	
Page Mode Current	I <sub>CC7</sub>	—	760	—	680	—	480	—	480	—	416	mA	t <sub>PC</sub> = min	1, 3
Input Leakage Current	I <sub>LI</sub>	-10	10	-10	10	-10	10	-10	10	-10	10	μA	0V ≤ V <sub>IN</sub> ≤ 7V	
Output Leakage Current	I <sub>LO</sub>	-10	10	-10	10	-10	10	-10	10	-10	10	μA	0V ≤ V <sub>OUT</sub> ≤ 7V D <sub>out</sub> = Disable	
Output High Voltage	V <sub>OH</sub>	2.4	V <sub>CC</sub>	2.4	V <sub>CC</sub>	2.4	V <sub>CC</sub>	2.4	V <sub>CC</sub>	2.4	V <sub>CC</sub>	V	High I <sub>out</sub> = -5 mA	
Output Low Voltage	V <sub>OL</sub>	0	0.4	0	0.4	0	0.4	0	0.4	0	0.4	V	Low I <sub>out</sub> = 4.2 mA	

Notes: 1. I<sub>CC</sub> depends on output load condition when the device is selected, I<sub>CC</sub> max is specified at the output open condition.

2. Address can be changed less than three times while RAS = V<sub>IL</sub>.

3. Address can be changed once or less while CAS = V<sub>IH</sub>.

• Capacitance (T<sub>A</sub> = 25°C, V<sub>CC</sub> = 5V ± 5%)

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Parameter	Symbol	Typ	Max	Unit	Unit
Input Capacitance (Address)	C <sub>I1</sub>	—	121	pF	1
Input Capacitance ( $\overline{WE}$ )	C <sub>I2</sub>	—	137	pF	1
Input Capacitance ( $\overline{RAS}$ )	C <sub>I3</sub>	—	48	pF	1
Input Capacitance ( $\overline{CAS}$ )	C <sub>I4</sub>	—	48	pF	1
Output Capacitance (DQ <sub>0</sub> -DQ <sub>31</sub> )	C <sub>I/O</sub>	—	17	pF	1, 2

Notes: 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.

2. CAS = V<sub>IH</sub> to disable D<sub>out</sub>.

• AC Characteristics (T<sub>A</sub> = 0 to +70°C, V<sub>CC</sub> = 5V ± 5%, V<sub>SS</sub> = 0V)<sup>1, 12</sup>

Read, Write and Refresh Cycle (Common Parameters)

Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Random Read or Write Cycle Time	t <sub>RC</sub>	125	—	140	—	160	—	190	—	220	—	ns	
RAS Precharge Time	t <sub>RP</sub>	55	—	60	—	70	—	80	—	90	—	ns	
RAS Pulse Width	t <sub>RAS</sub>	60	10000	70	10000	80	10000	100	10000	120	10000	ns	
CAS Pulse Width	t <sub>CAS</sub>	20	10000	20	10000	25	10000	25	10000	30	10000	ns	
Row Address Setup Time	t <sub>ASR</sub>	0	—	0	—	0	—	0	—	0	—	ns	
Row Address Hold Time	t <sub>RAH</sub>	10	—	10	—	12	—	15	—	15	—	ns	
Column Address Setup Time	t <sub>ASC</sub>	0	—	0	—	0	—	0	—	0	—	ns	
Column Address Hold Time	t <sub>CAH</sub>	15	—	15	—	20	—	20	—	25	—	ns	



Read, Write and Refresh Cycle (Common Parameters) (continued)

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Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
RAS to CAS Delay Time	t <sub>RC</sub> D	20	40	20	50	22	55	25	75	25	90	ns	8
RAS to Column Address Delay Time	t <sub>RC</sub> AD	15	30	15	35	17	40	20	55	20	65	ns	9
RAS Hold Time	t <sub>RS</sub> H	20	—	20	—	25	—	25	—	30	—	ns	
CAS Hold Time	t <sub>CS</sub> H	60	—	70	—	80	—	100	—	120	—	ns	
CAS to RAS Precharge Time	t <sub>CR</sub> P	10	—	10	—	10	—	10	—	10	—	ns	
Transition Time (Rise and Fall)	t <sub>T</sub>	3	50	3	50	3	50	3	50	3	50	ns	7
Refresh Period	t <sub>REF</sub>	—	8	—	8	—	8	—	8	—	8	ns	15

• Read Cycle

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Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Access Time from RAS	t <sub>RA</sub> C	—	60	—	70	—	80	—	100	—	120	ns	2, 3
Access Time from CAS	t <sub>CA</sub> C	—	20	—	20	—	25	—	25	—	30	ns	3, 4
Access Time from Address	t <sub>AA</sub>	—	30	—	35	—	40	—	45	—	55	ns	3, 5
Read Command Setup Time	t <sub>RC</sub> S	0	—	0	—	0	—	0	—	0	—	ns	
Read Command Hold Time to CAS	t <sub>RC</sub> H	0	—	0	—	0	—	0	—	0	—	ns	
Read Command Hold Time to RAS	t <sub>RR</sub> H	10	—	10	—	10	—	10	—	10	—	ns	
Column Address to RAS Lead Time	t <sub>RA</sub> L	30	—	35	—	40	—	45	—	55	—	ns	
Output Buffer Turn-Off Time	t <sub>OFF</sub>	—	20	—	20	—	20	—	25	—	30	ns	6

• Write Cycle

Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Write Command Setup Time	t <sub>WC</sub> S	0	—	0	—	0	—	0	—	0	—	ns	10
Write Command Hold Time	t <sub>WC</sub> H	15	—	15	—	20	—	20	—	25	—	ns	
Write Command Pulse Width	t <sub>WP</sub>	10	—	10	—	15	—	15	—	20	—	ns	
Data-in Setup Time	t <sub>DS</sub>	0	—	0	—	0	—	0	—	0	—	ns	11
Data-in Hold Time	t <sub>DH</sub>	15	—	15	—	20	—	20	—	25	—	ns	11

• Refresh Cycle

Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
CAS Setup Time (CAS Before RAS Refresh Cycle)	t <sub>CS</sub> R	10	—	10	—	10	—	10	—	10	—	ns	
CAS Hold Time (CAS Before RAS Refresh Cycle)	t <sub>CH</sub> R	15	—	15	—	20	—	20	—	25	—	ns	
RAS Precharge to CAS Hold Time	t <sub>RP</sub> C	10	—	10	—	10	—	10	—	10	—	ns	



## • Fast Page Mode Cycle

## HITACHI/ LOGIC/ARRAYS/MEM 51E D T-46-23-18

Parameter	Symbol	-6A		-7A		-8A		-10A		-12A		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Fast Page Mode Cycle Time	$t_{PC}$	45	—	50	—	55	—	55	—	65	—	ns	
Fast Page Mode $\overline{CAS}$ Precharge Time	$t_{CP}$	10	—	10	—	10	—	15	—	10	—	ns	
Fast Page Mode $\overline{RAS}$ Pulse Width	$t_{RASC}$	—	100000	—	100000	—	100000	—	100000	—	100000	ns	12
Access Time from $\overline{CAS}$ Precharge	$t_{ACP}$	—	40	—	45	—	50	—	50	—	60	ns	13
$\overline{RAS}$ Hold Time from $\overline{CAS}$ Precharge	$t_{RHCP}$	40	—	45	—	50	—	50	—	60	—	ns	

- Notes:
1. AC measurements assume  $t_T = 5$  ns.
  2. Assumes that  $t_{RCD} \leq t_{RCD}(\max)$  and  $t_{RAD} \leq t_{RAD}(\max)$ . If  $t_{RCD}$  or  $t_{RAD}$  is greater than the maximum recommended value shown in this table,  $t_{RAC}$  exceeds the value shown.
  3. Measured with a load circuit equivalent to 2 TTL loads and 100 pF.
  4. Assumes that  $t_{RCD} \geq t_{RCD}(\max)$  and  $t_{RAD} \leq t_{RAD}(\max)$ .
  5. Assumes that  $t_{RCD} \leq t_{RCD}(\max)$  and  $t_{RAD} \geq t_{RAD}(\max)$ .
  6.  $t_{OFF}(\max)$  is defined as the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.
  7.  $V_{IH}(\min)$  and  $V_{IL}(\max)$  are reference levels for measuring timing of input signals. Also, transition times are measured between  $V_{IH}$  and  $V_{IL}$ .
  8. Operation with the  $t_{RCD}(\max)$  limit insures that  $t_{RAC}(\max)$  can be met,  $t_{RCD}(\max)$  is specified as a reference point only, if  $t_{RCD}$  is greater than the specified  $t_{RCD}(\max)$  limit, then access time is controlled exclusively by  $t_{CAC}$ .
  9. Operation with the  $t_{RAD}(\max)$  limit insures that  $t_{RAC}(\max)$  can be met,  $t_{RAD}(\max)$  is specified as a reference point only, if  $t_{RAD}$  is greater than the specified  $t_{RAD}(\max)$  limit, then access time is controlled exclusively by  $t_{AA}$ .
  10. Early write cycle only ( $t_{WCS} \geq t_{WCS}(\min)$ ).
  11. These parameters are referenced to  $\overline{CAS}$  leading edge in an early write cycle.
  12. An initial pause of 100  $\mu$ s is required after power up followed by a minimum of eight initialization cycles (any combination of cycles containing  $\overline{RAS}$  clock such as  $\overline{RAS}$  only refresh).
  13.  $t_{RASC}$  is determined by  $\overline{RAS}$  pulse width in fast page mode cycles.
  14. Access time is determined by the longer of  $t_{AA}$  or  $t_{CAC}$  or  $t_{ACP}$ .
  15.  $t_{REF}$  is determined by 512 refresh cycles.

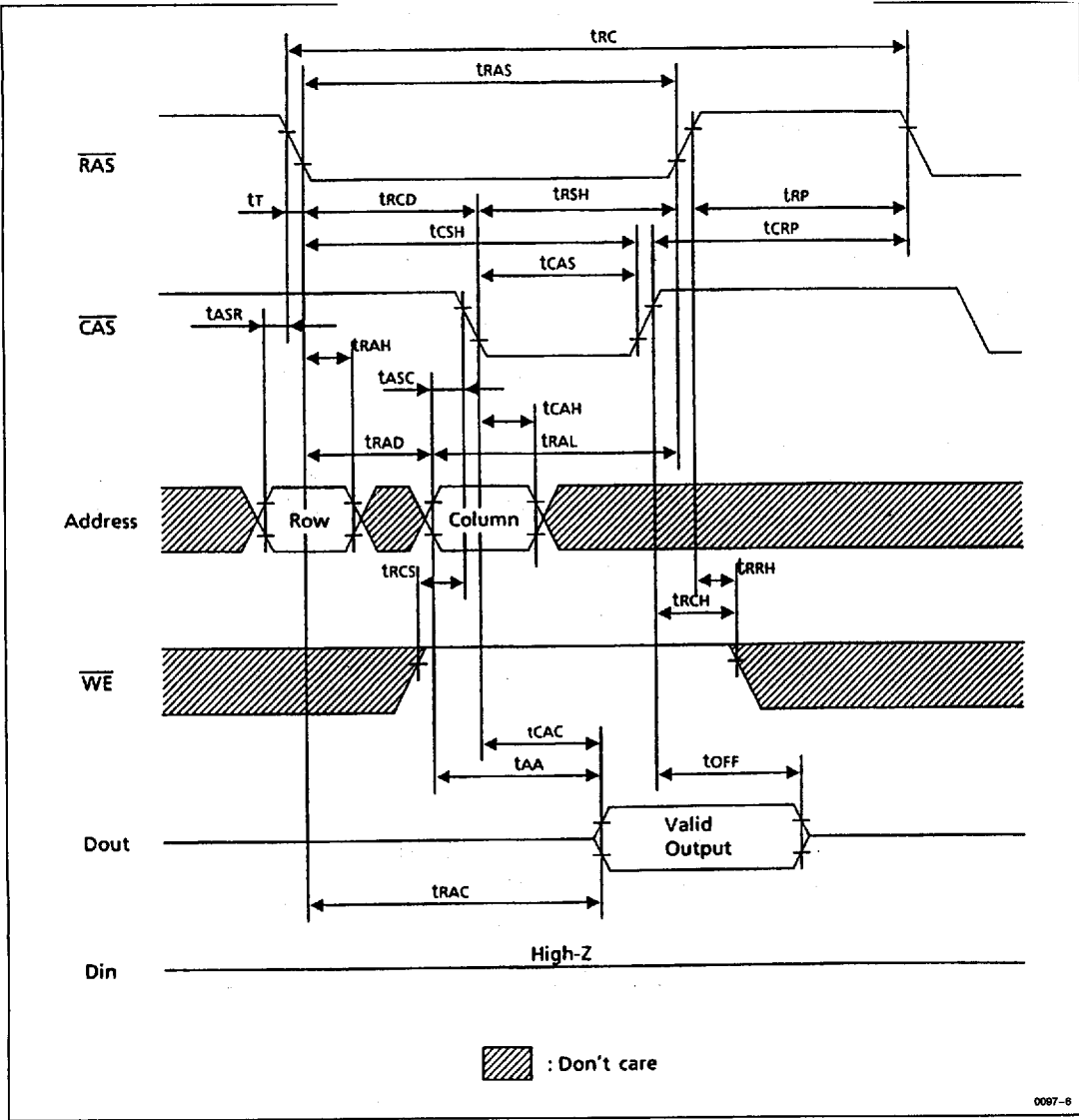


■ TIMING WAVEFORMS

• Read Cycle

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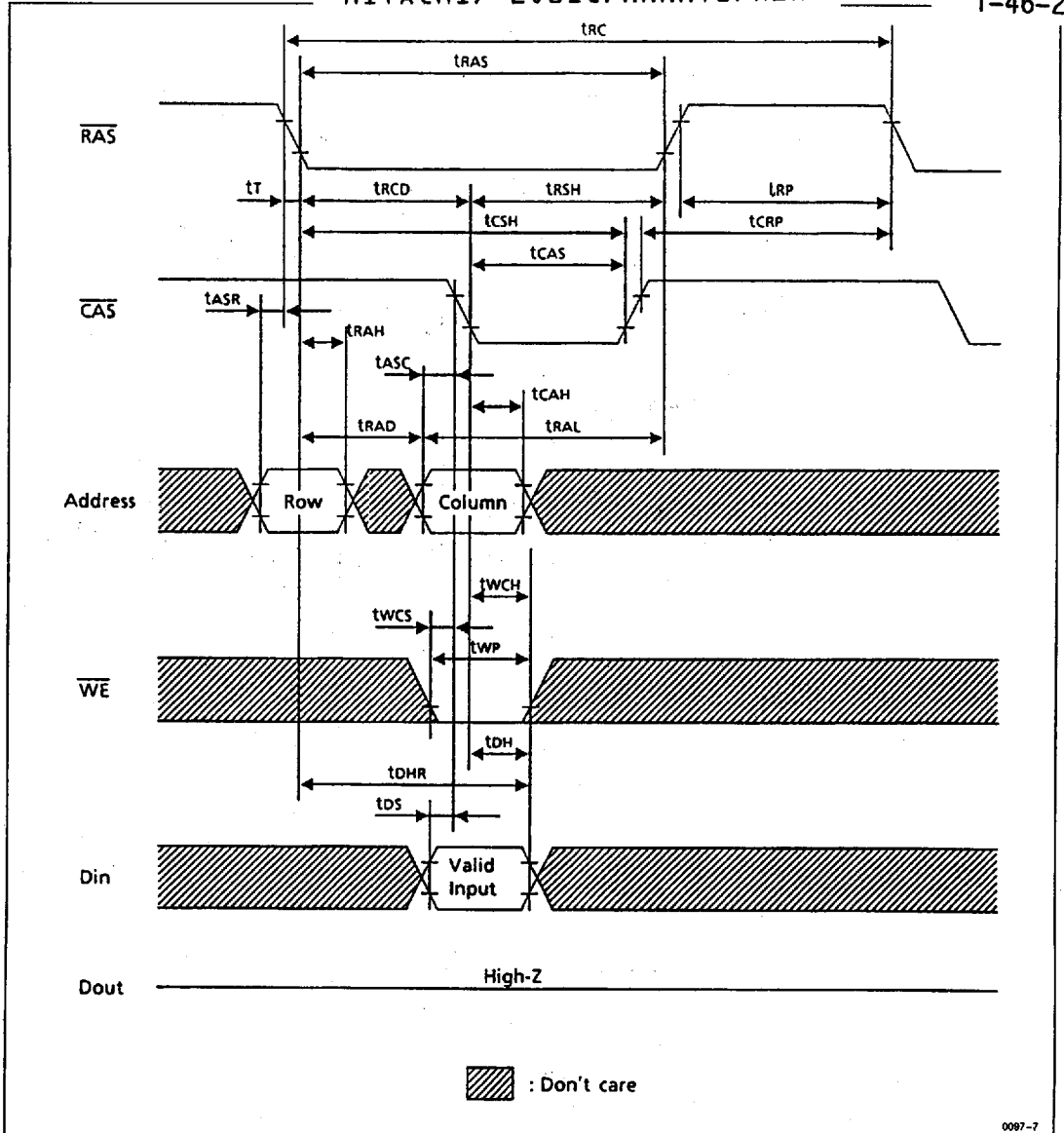
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• Early Write Cycle

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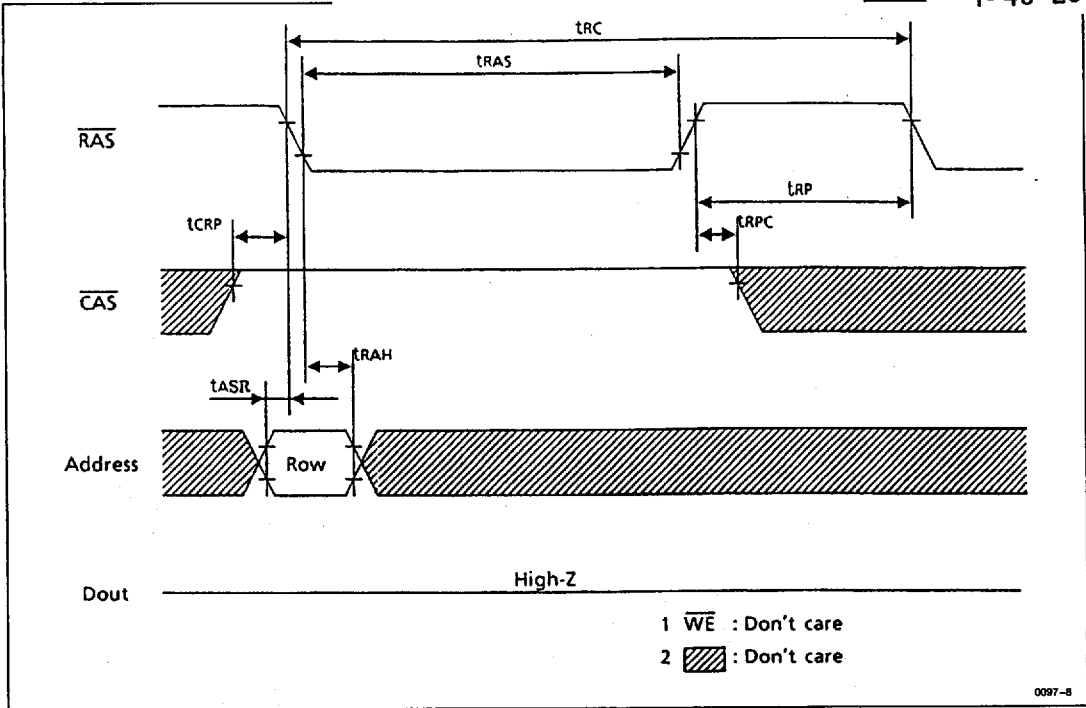




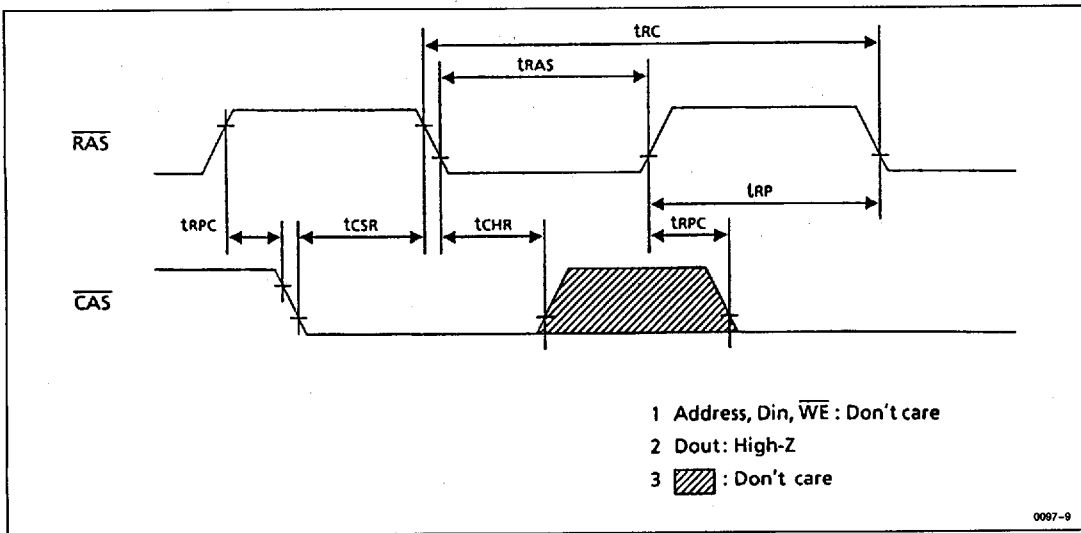
•  $\overline{\text{RAS}}$  Only Refresh Cycle

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•  $\overline{\text{CAS}}$  Before  $\overline{\text{RAS}}$  Refresh Cycle

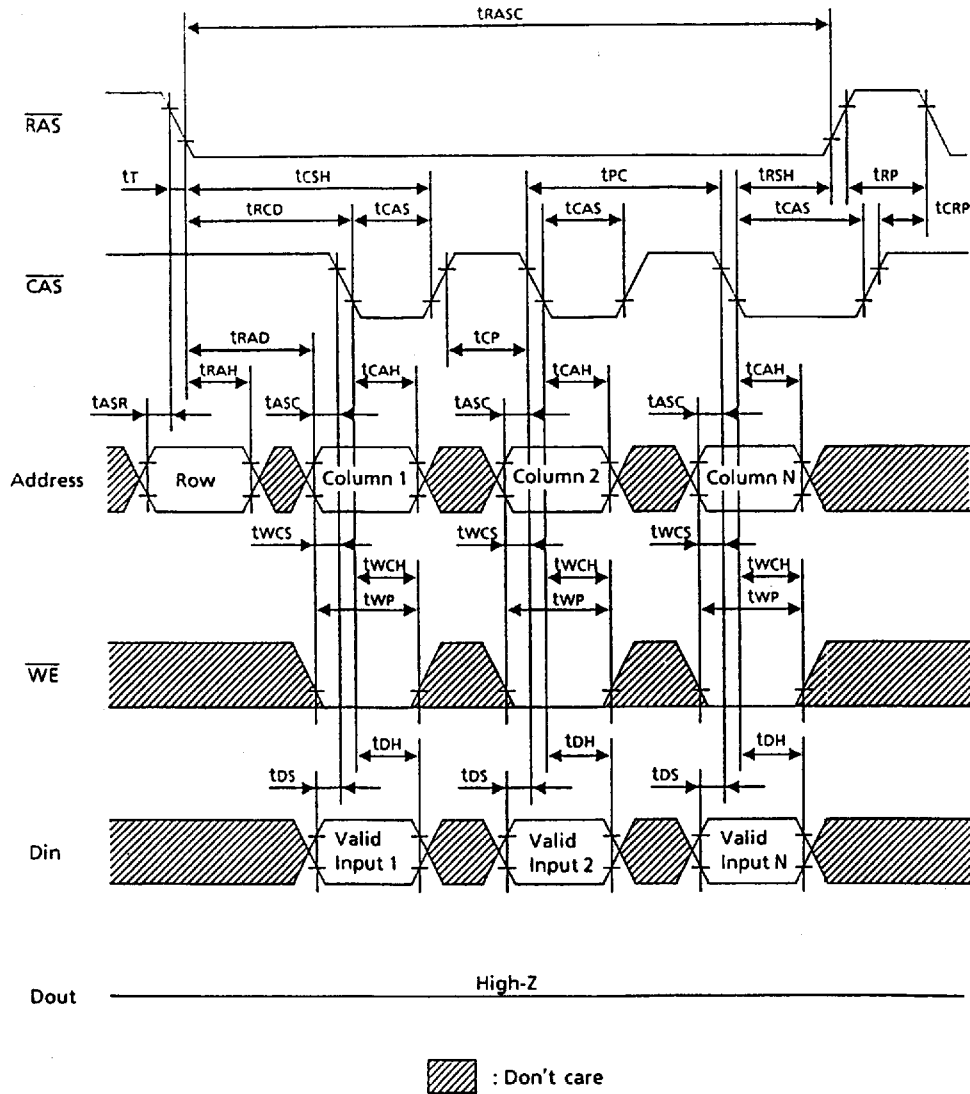




• Fast Page Mode Early Write Cycle

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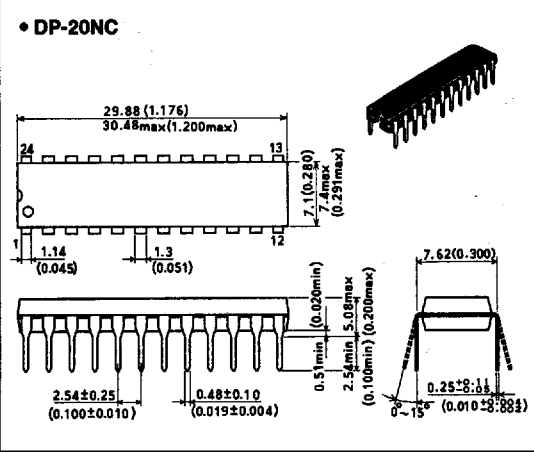
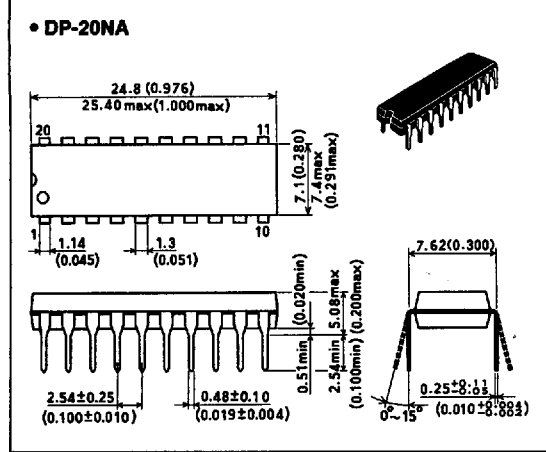
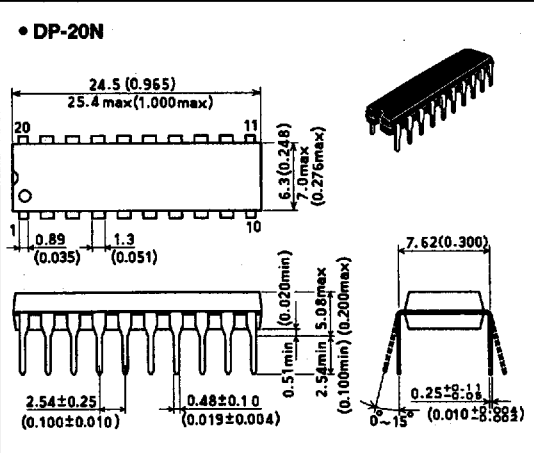
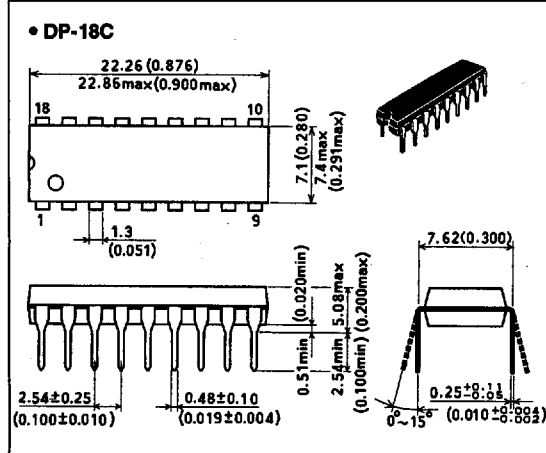
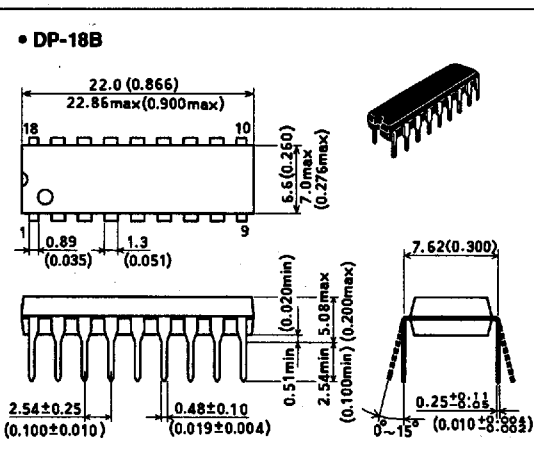
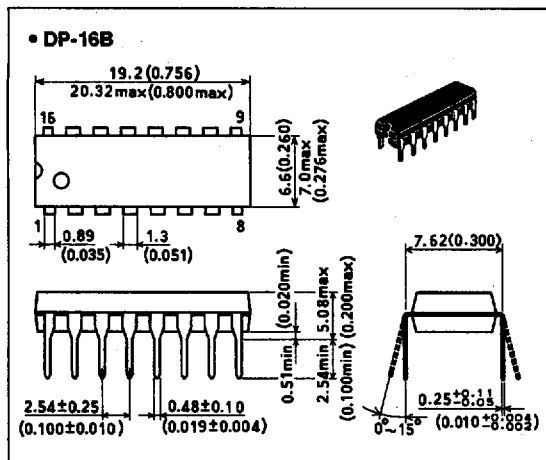
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T-90-20

Unit: mm (inch) Scale 3/2

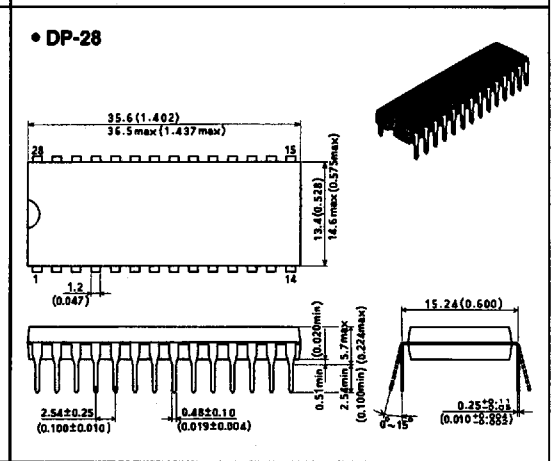
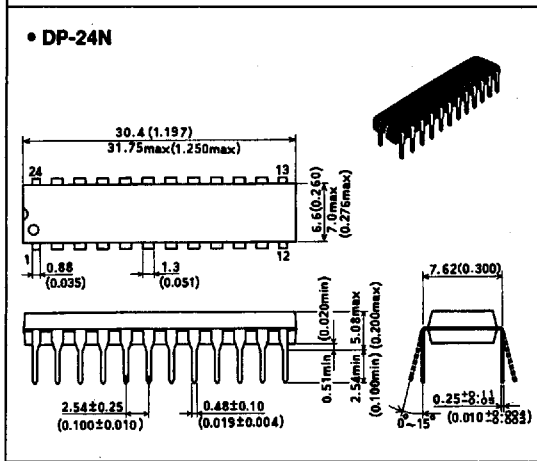
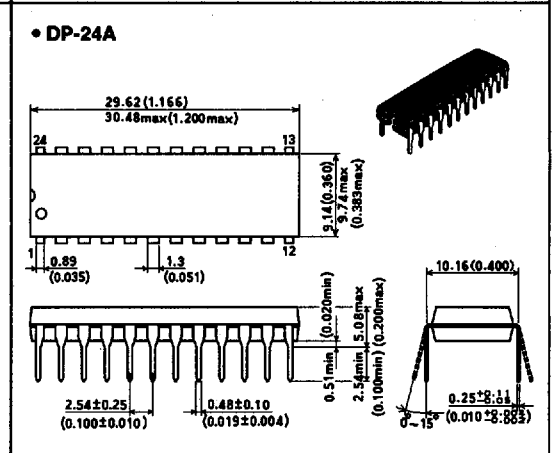
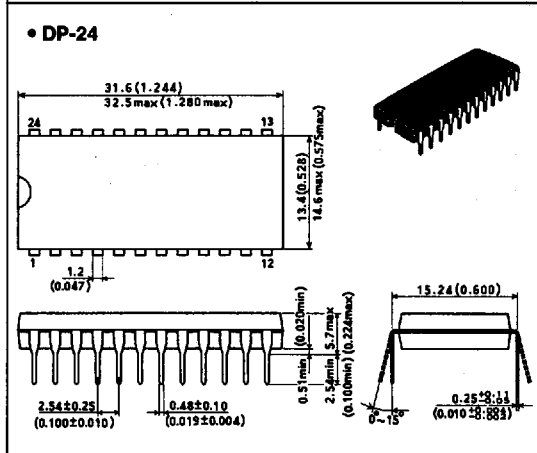
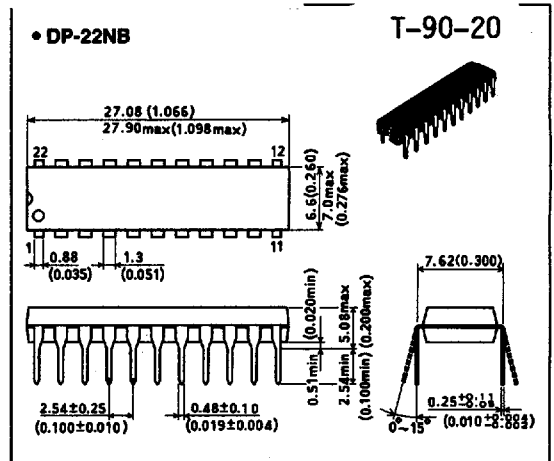
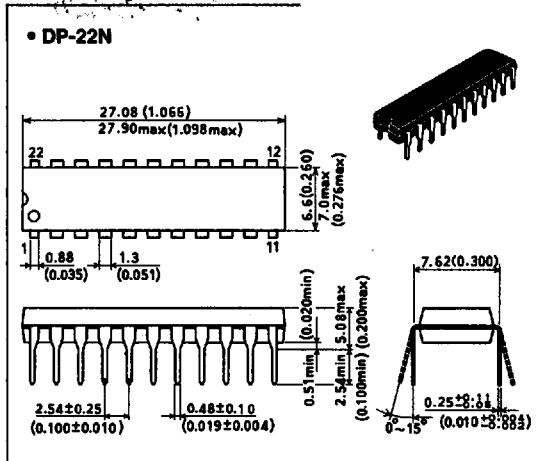
• Dual-in-line Plastic



• Dual-in-line Plastic

HITACHI/ LOGIC/ARRAYS/MEM

Unit: mm (inch) Scale 3/2



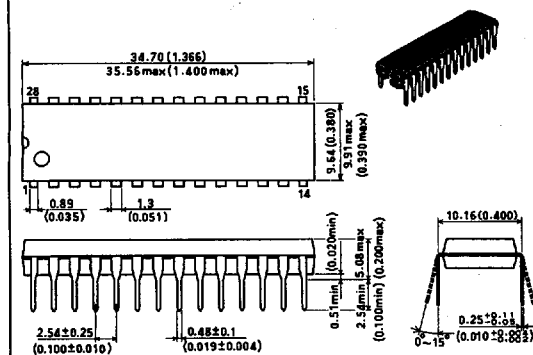
• Dual-in-line Plastic

HITACHI/ LOGIC/ARRAYS/MEM

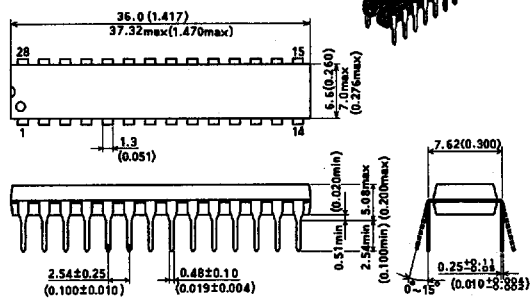
Unit: mm (inch) Scale 3/2

T-90-20

## • DP-28C



## • DP-28N

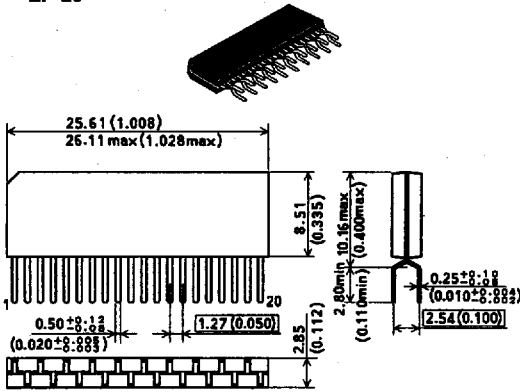


• Zigzag-in-line Plastic

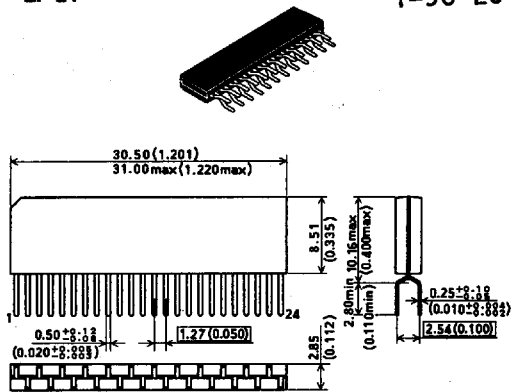
HITACHI/ LOGIC/ARRAYS/MEM

Unit: mm (inch) Scale 3/2

• ZP-20

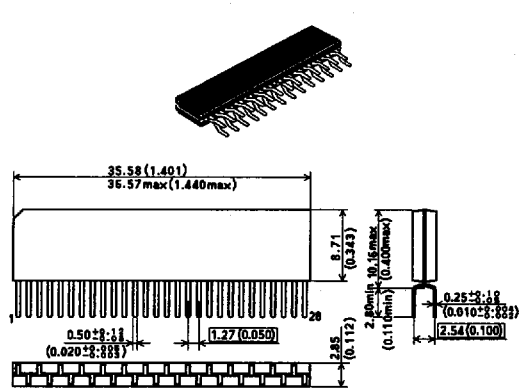


• ZP-24

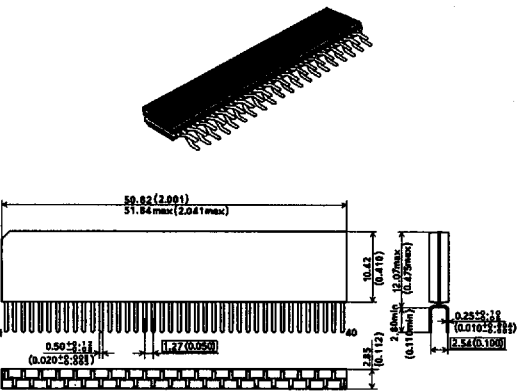


T-90-20

• ZP-28



• ZP-40



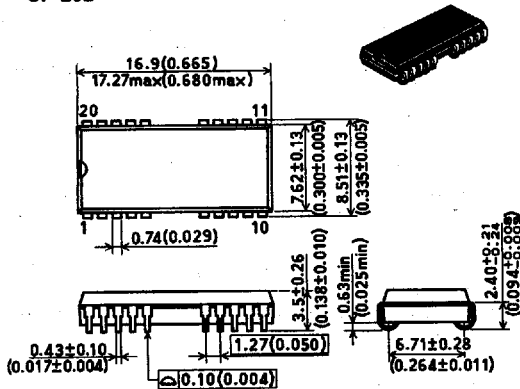
• Flat Package (J-bend Leads)

HITACHI/ LOGIC/ARRAYS/MEM

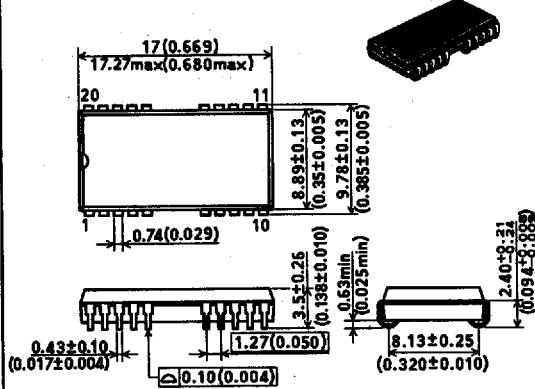
Unit: mm (inch) Scale 3/2

T-90-20

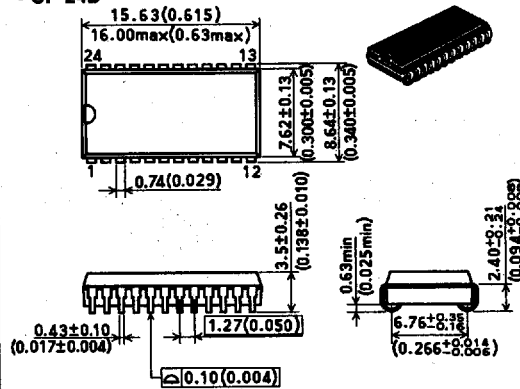
## • CP-20D



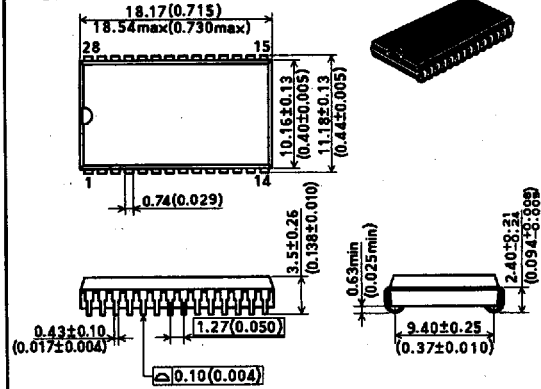
## • CP-20DA



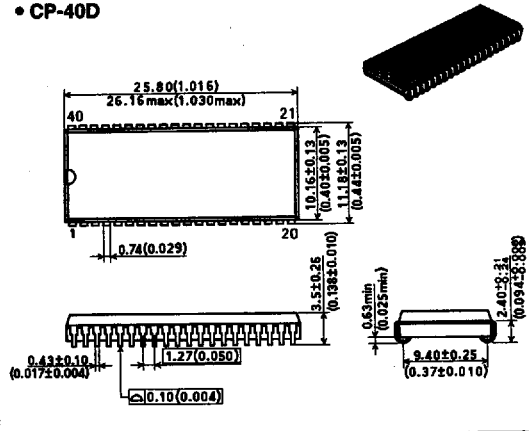
## • CP-24D



## • CP-28D



## • CP-40D


**HITACHI**



• TSP (Thin Small Outline Package) HITACHI/ LOGIC/ARRAYS/MEM Unit: mm (inch) Scale 3/2

